EAST SEARCH

S10 \$1 \$2 \$3 \$3 \$4 \$5 \$6 \$7 \$8 \$9 1254 59 6387 30<u>4</u> 82 38 67 48 48 93 93 87 10 10 54 30 30 33 89 89 89 89 89 89 89 167 2167 127 S33 and (circuit with partition\$1) S7 or S14 or S15 or S16 or S23 S33 and (on-board with processing\$1) S33 and (circuit with element\$1) circuit\$1 with emulat\$3 S6 or S8 or S9 or S10 or S11 or S12 or S13 or S17 or S18 or S19 or S20 or S21 or S22 or S2 US-PGPUB; S5 and (EDA with software) S5 and (workstation) S5 and ((emulat\$3 near2 system) with board\$1) S5 and (local\$2 with (generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulii)) S5 and ((generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulii)) S5 and (test\$3 with (vector\$1 or stimulus or stimulii)) S5 and (on-chip with processing) S5 and (board with circuit\$1) S5 and ((detect\$3 or report\$3) with event\$1) S5 and ((analyz\$3 or analysis) with data) S5 and (retriev\$3 with state\$1) S5 and ((monitor\$3 or report\$3 or test\$3) with command\$1) S5 and (on-board with processing\$1) S5 and (circuit with partition\$1) S5 and (circuit with element\$1) circuit\$1 with emulat\$3 Search String S33 and (reconfigurable with (togic or interconnect\$1)) S30 or S32 S31 and (distributed with (emulat\$3 or processing)) S29 and (distributed with (emulat\$3 or processing)) ((integrated or digital) near2 circuit\$1) with emulat\$3 S25 or S27 S25 and S26 S5 and (local\$2 with (monitor\$3 or analyz\$3 or analysis or report\$3)) S5 and ((monitor\$3 or report\$3 or test\$3) with request\$1) S5 and (element\$1 with state\$1) S5 and (reconfigurable with (logic or interconnect\$1)) S2 or S4 S3 and (distributed with (emulat\$3 or processing)) S1 and (distributed with (emulat\$3 or processing)) ((integrated or digital) near2 circuit\$1) with emulat\$3 US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; US-PGPUB; US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB **Databases** US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB USPAT; EPO; USPAT; EPO; USPAT; EPO; JPO; DERWENT; IBM_TDB JPO; DERWENT; IBM_TDB JPO; DERWENT; IBM_TDB JPO; DERWENT; IBM_TDB J P O J P O JPO; DERWENT; JPO; DERWENT; IBM_TDB JPO; DERWENT; IBM_TDB JPO; DERWENT; JPO; DERWENT; IBM_TDB DERWENT; IBM_TDB DERWENT; IBM_TDB IBM_TDB IBM_TDB

| \$73 \$74 \$75 | S71 S72 | S69 S70 | S67 | S64 | S62 | S61 | S60 | S59 | S58 | S57 | S56 | S55 | S54 | S53 | S52 | S51 | S49 | S48 | S46 | S44 | S43 | S42 | S41 | S40 | S39 | S38 |
|--|--|---|--|--|--|---|----------------------------------|--------------|--------------------|---------------------------------|---|-----------------------------|-----------------------|--|--|--|--|--|-----------------------------------|---|--|---|---|--|--|---|
| 53 53 | 32 32 | 5 5 5 | 321 | 6696 62 | 8 න | 1318 | 4 | 167 | 133 | 210 | 167 | œ | 89 | 25 | ω | 38 | 30 | 5 2 | 7 | 87 | 20 | 93 | 27 | 48 | 67 | 38 |
| S63 and ((generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulii)) S63 and ((local\$2 or on-chip) with (generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulus or S65 or S66 or S67 or S68 | S63 and (on-chip with processing) S63 and (test\$3 with (vector\$1 or stimulus or stimulii)) | S60 or S62 S63 and (reconfigurable with (logic or interconnect\$1)) | S61 and (distributed with (emulat\$3 or processing)) | S58 and (distributed with (emulat\$3 or processing)) circuit\$1 with emulat\$3 | S58 and (distributed with (emulat\$3 or processing)) | ((integrated or digital) near2 circuit\$1) with emulat\$3 | 6,265,894.pn. or "5,777,489".pn. | \$53 or \$55 | S53 and S54 | S35 or S42 or S43 or S44 or S51 | S34 or S36 or S37 or S38 or S39 or S40 or S41 or S45 or S46 or S47 or S48 or S49 or S50 o | S33 and (EDA with software) | S33 and (workstation) | S33 and ((emulat\$3 near2 system) with board\$1) | S33 and (local\$2 with (generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulii)) | S33 and ((generat\$3 or produc\$3) with (vector\$1 or stimulus or stimulii)) | S33 and (test\$3 with (vector\$1 or stimulus or stimulii)) | S33 and (local\$2 with (monitor\$3 or analyz\$3 or analysis or report\$3)) | S33 and (on-chip with processing) | S33 and (board with circuit\$1) | S33 and ((detect\$3 or report\$3) with event\$1) | S33 and ((analyz\$3 or analysis) with data) | S33 and (retriev\$3 with state\$1) | S33 and ((monitor\$3 or report\$3 or test\$3) with command\$1) | S33 and ((monitor\$3 or report\$3 or test\$3) with request\$1) | S33 and (element\$1 with state\$1) |
| US-PGPUB; USPAT; EPO; JPO; DERWENT; US-PGPUB; USPAT; EPO; JPO; DERWENT; US-PGPUB; USPAT; EPO; JPO; DERWENT; | EPO; JPO; DERWENT; EPO; JPO; DERWENT; | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | EPO; JPO; DERWENT; | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | EPO; JPO; DERWENT; | DERWENT; IBM | EPO; JPO; DERWENT; | | EPO; JPO; DERWENT; | DERWENT; IBN | US-PGPUB; USPAT; EPO; JPO; DERWENT; | EPO; JPO; DERWENT; | EPO; JPO; DERWENT; | DERWENT; | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | DERWENT; | EPO; JPO; DERWENT; | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |

10/003184 Frederic Reblewski

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6/19/2006

| US 20040220891 A1 | US 20050071716 A1 | Document Kind Codes Title | Results of search set S115 |
|---|--|---------------------------|----------------------------|
| US 20040220891 A1 Neural networks decoder | US 20050071716 A1 Testing of reconfigurable logic and interconnect sources | Title | <u>t S115</u> |

Issue Date Current OR 20050331 714/725 20041223 703/23 20041104 706/12

Abstract

Page 2 of 4

| 5452239 5377306 5357597 5222193 | US 5621651 A US 5517597 A US 5475793 A | 5761077 5684721 | 5841670 5838948 | US 5940603 A US 5937154 A | US 5956518 A US 5943490 A | US 5960191 A | | US RE37488 E | US 6415188 B1 | US 6496918 B1 | US 6567962 B2 | US 6684318 B2 | US 6694464 B1 | US 6732068 B2 | US 6920416 B1 | US 6922664 B1 | US 20020066065 A1 | US 20020161568 A1 | US 20020177990 A1 | US 20030074178 A1 | US 20030105617 A1 | US 20030149675 A1 | US 20040034841 A1 | US 20040044514 A1 | US 20040078187 A1 | US 20040181497 A1 |
|--|---|---|--|---|--|---|---|---------------------|---|---|--|---|--|---|---|--|--|---|---|---|---|--|--|--|--|-------------------|
| Method of removing gated clocks from the clock nets of a netlist for timing sensitive implemen Heuristic processor Convolutional expert neural system (ConExNS) Training system for neural networks and the like | Electronic stritulation and emulation system Emulation devices, systems and methods with distributed control of test interfaces in clock do Convolutional expert neural system (ConExNS) Heuristic digital processor using non-linear transformation | Graph partitioning engine based on programmable gate arrays Electronic systems and emulation and testing devices, cables, systems and methods | Emulation devices, systems and methods with distributed control of clock domains System and method for simulation of computer systems combining hardware and software into | Method and apparatus for emulating multi-ported memory circuits Manufacturing functional testing of computing devices using microprogram based functional te | Intermediate-grain reconfigurable processing device Distributed logic analyzer for use in a hardware logic emulation system | System and method for simulation of integrated naroware and software components Emulation system with time-multiplexed interconnect | Intermediate-grain reconfigurable processing device | Heuristic processor | Method and apparatus for multi-sensor processing Emulation system with time-multiplexed interconnect | Intermediate-grain reconfigurable processing device | Method, apparatus, and program for multiple clock domain partitioning through retiming | Intermediate-grain reconfigurable processing device | Method and apparatus for dynamically testing electrical interconnect | Memory circuit for use in hardware emulation system | Electronic systems testing employing embedded serial scan generator | Method and apparatus for multi-sensor processing | Method apparatus and program for multiple clock domain partitioning through retiming | Memory circuit for use in hardware emulation system | Distributed logic analyzer for use in a hardware logic emulation system | Emulation system with time-multiplexed interconnect | Hardware acceleration system for logic simulation | Method for detecting bus contention from KTL description Processing device with intuitive learning capability | Emulation components and system including distributed event monitoring, and testing of an IC | Polymorphic computational system and method in signals intelligence analysis | Emulation components and system including distributed routing and configuration of emulation Real time emulation of coherence directories using alphal sparse directories. | Neural networks |
| | 19970902 19970415 703/23 19960514 706/26 19951212 706/14 | 19980602 716/7 19971104 703/23 | | | 19990921 712/15 19990824 703/28 | 19990928 703/28 | | 20011225 706/14 | | | 20030527 716/6 | | | 20041214 702/189 | | | 20020822 /03/28 | | - | | _ | 20031218 710/107 | | | 20040422 703/28 | 20040916 706/23 |

| US 4802103 A US 4773024 A | US 4896053 A | US 4961002 A | US 5087826 A | US 5113500 A |
|---|--|---|---|--|
| Brain learning and recognition emulation circuitry and method of recognizing events Brain emulation circuit with reduced confusion | Solitary wave circuit for neural network emulation | Synapse cell employing dual gate transistor structure | Multi-layer neural network employing multiplexed output neurons | Multiple cooperating and concurrently operating processors using individually dedicated memory |
| 19890131 706/38 19880920 706/20 | 19900123 706/38 | 19901002 365/185.03 | 19920211 706/38 | 19920512 710/305 |

10/003184 Frederic Reblewski

Interperence checked

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| On and (on-comproment) | L# \$75 \$76 \$77 | Hits Search String ((integrated or digital) near2 circuit\$1) with emulat\$3 27 S75 and (distributed with (emulat\$3 or processing)) 3 S77 and (on-chip CLM) |
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| S75 and (distributed with (emulat\$3 or processing)) S76 and (on-chip with processing) S77 and (on-chip.CLM.) | | |
| 27 3 | S75 | |
| 3 S76 and (on-chip with processing) 3 S77 and (on-chip.CLM.) | S76 | |
| 3 S77 and (on-chip.CLM.) | S77 | 3 S76 and (on-chip with processing) |
| | S78 | 3 S77 and (on-chip.CLM.) |

EAST SEARCH

6/19/2006

| US 6684318 B2 Intermediate-grain reconfigurable processing device | US 6694464 B1 Method and apparatus for dynamically testing electrical interconnect | US 6732068 B2 Memory circuit for use in hardware emulation system | US 6832178 B1 Method and apparatus for multi-sensor processing | US 6920416 B1 Electronic systems testing employing embedded serial scan generator | US 6922664 B1 Method and apparatus for multi-sensor processing | US 20020066065 A1 Method, apparatus, and program for multiple clock domain partitioning through retiming | US 20020116168 A1 METHOD AND SYSTEM FOR DESIGN VERIFICATION OF ELECTRONIC CIRCUITS | US 20020161568 A1 Memory circuit for use in hardware emulation system | US 20020177990 A1 Distributed logic analyzer for use in a hardware logic emulation system | US 20030074178 A1 Emulation system with time-multiplexed interconnect | US 20030105617 A1 Hardware acceleration system for logic simulation | US 20030149675 A1 Processing device with intuitive learning capability | US 20030233504 A1 Method for detecting bus contention from RTL description | US 20040034841 A1 Emulation components and system including distributed event monitoring, and testing | US 20040044514 A1 Polymorphic computational system and method in signals intelligence analysis | US 20040059876 A1 Real time emulation of coherence directories using global sparse directories | US 20040078187 A1 Emulation components and system including distributed routing and configuration of en | US 20040181497 A1 Neural networks | US 20040220891 A1 Neural networks decoder | US 20040260530 A1 Distributed configuration of integrated circuits in an emulation system | US 20050071716 A1 Testing of reconfigurable logic and interconnect sources | Results of search set S115 Document Kind Codes Title |
|---|--|---|--|---|--|--|--|---|---|---|---|--|--|---|--|--|---|-----------------------------------|---|---|--|---|
| ssing device | esting electrical interconnect | lation system | processing | mbedded serial scan generator | processing | ultiple clock domain partitioning through retiming | VERIFICATION OF ELECTRONIC CIRCUITS | llation system | ardware logic emulation system | interconnect | simulation | g capability | m RTL description | uding distributed event monitoring, and testing of an II | method in signals intelligence analysis | tories using global sparse directories | uding distributed routing and configuration of emulatic | | | ircuits in an emulation system | rconnect sources | <u> </u> |
| 20040127 712/15 | 20040217 714/725 | 20040504 703/24 | 20041214 702/189 | 20050719 703/13 | 20050726 703/13 | 20020530 716/6 | 20020822 703/28 | 20021031 703/25 | 20021128 703/28 | 20030417 703/25 | 20030605 703/14 | 20030807 706/2 | 20031218 710/107 | 20040219 716/8 | | 20040325 711/141 | 20040422 703/28 | 20040916 706/23 | 20041104 706/12 | 20041223 703/23 | 20050331 714/725 | Issue Date Current OR |
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| US 20040260530 A1 US 20040078187 A1 US 20040034841 A1 | US 6571370 B2 US 6567962 B2 US 6496918 B1 US 6415188 B1 US 6377912 B1 US 6266760 B1 US 6952524 A US 5960191 A US 5943490 A US 5937154 A US 5937154 A US 5838948 A US 5663900 A US 5663900 A US 5663900 A US 56761077 A US 5663900 A US 567730 A US 5475793 A US 5475793 A US 5475793 A US 5377306 A US 54961002 A US 4896053 A US 4896053 A US 4896053 A US 4896053 A US 48773024 A | |
|---|--|--|
| Distributed configuration of integrated circuits in an emulation system Emulation components and system including distributed routing and configuration of emulatic Emulation components and system including distributed event monitoring, and testing of an I | Method and system for design verification of electronic circuits Method, apparatus, and program for multiple clock domain partitioning through retiming Intermediate-grain reconfigurable processing device Method and apparatus for multi-sensor processing device Method and apparatus for multiplexed interconnect Heuristic processor Intermediate-grain reconfigurable processing device System and method for simulation of integrated hardware and software components Emulation system with time-multiplexed interconnect Intermediate-grain reconfigurable processing device System and method for simulation grain therefore memory circuits Method and apparatus for emulating multi-ported memory circuits Method and apparatus for emulating multi-ported memory circuits Manufacturing functional testing of computing devices using microprogram based functional temulation devices, systems and methods with distributed control of clock domains System and method for simulation of computer systems combining hardware and software in Graph partitioning engine based on programmable gate arrays Electronic simulation and emulation system Emulation devices, systems and methods with distributed control of test interfaces in clock of convolutional expert neural system (ConExNS) Heuristic digital processor using non-linear transformation Method of removing gated clocks from the clock nets of a netlist for timing sensitive implement Heuristic processor Convolutional expert neural system (ConExNS) Training system for neural networks and the like Multi-layer neural network employing multiplexed output neurons Synapse cell employing dual gate transistor structure Solitary wave circuit for neural network emulation circuity and method of recognizing events Brain emulation circuit with reduced confusion | |
| 20041223 703/23 20040422 703/28 20040219 716/8 | 20030527 716/4 20030520 716/6 20021217 712/15 20020702 700/67 20020702 703/28 20011225 706/14 20010724 712/15 20000418 703/22 19990824 703/28 19990817 716/5 19990810 714/30 19981124 703/23 19981117 703/27 19980602 716/7 19971104 703/23 19970415 703/23 19970415 703/23 19970415 703/23 19960514 706/26 19951212 706/14 19951212 706/14 19941018 706/25 19930622 706/25 19930622 706/38 19901002 365/185.03 19900123 706/38 19800131 706/38 19800131 706/38 | |